



**international**

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**reliability physics symposium**

NEWS RELEASE

**2006 INTERNATIONAL RELIABILITY PHYSICS SYMPOSIUM**

**RETURNS TO SILICON VALLEY**

*New General Chairperson Announced*

SAN JOSE, CALIF. – October 10, 2005 – The IEEE International Reliability Physics Symposium (IRPS) returns to Silicon Valley for its 44<sup>th</sup> annual conference from March 26 through March 30, 2006, at the McEnery Convention Center/Hilton San Jose in San Jose, California. This is the second consecutive year the IRPS has been held in Silicon Valley.

Dr. Carole D. Graas, Product Qualifications Manager in IBM's Systems and Technology Group, has been named this year's general chair for the 2006 IRPS.

“Silicon Valley nurtured the microelectronics industry and fostered important reliability issues,” said Graas, who also served as the general vice chair for the 2005 IRPS. “It's a perfect fit and only natural that IRPS engineers, scientists and researchers would want to return.”

Last year's symposium saw record attendance with over 700 industry professionals attending the week-long IRPS.

In addition to providing a platform for the latest findings in microelectronics reliability, IRPS gives the opportunity for “hands on” demonstrations of the latest reliability testing equipment as well as presentations from leading industry professionals.

Keynote speakers in the past have included David W. Yen, executive vice president of Sun Microsystems Scalable Systems Group (2005), Dr. Hans Stork, chief technology officer of Texas Instruments (2004), and Dr. Shang-yi Chiang, senior vice president and the head of the research and development group, of Taiwan Semiconductor Manufacturing Co., Ltd. (TSMC), and Mark T. Bohr, an Intel Fellow and director of process architecture and integration at Intel (both in 2003).

### **About IRPS**

For more than 40 years, IRPS has been one of the leading meetings for engineers in the area of electronic component reliability. IRPS promotes the comprehension of reliability and performance of integrated circuits and microelectronic assemblies through an improved understanding of failure mechanisms in the user's environment. Originally started in the early 1960's by the military and aerospace community, IRPS is now sponsored by IEEE Reliability Society and IEEE Electron Devices Society. All accepted IRPS papers will appear in the symposium proceedings publication, as well as on the Virtual IRPS DVD-ROM, which is available now for the previous 2004 IRPS.

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For further information, please visit the IRPS web site at [www.irps.org](http://www.irps.org) or contact:

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